

**DESCRIPTION**

The NE502 is a MOS monolithic integrated circuit, generally intended to delay analogue signals (e.g. delay time = 512/2f<sub>0</sub>).

It can be used with clock frequencies in the range 5kHz to 500kHz.

The device contains 512 stages, so the input signal can be delayed from 51.2ms to 0.512ms.

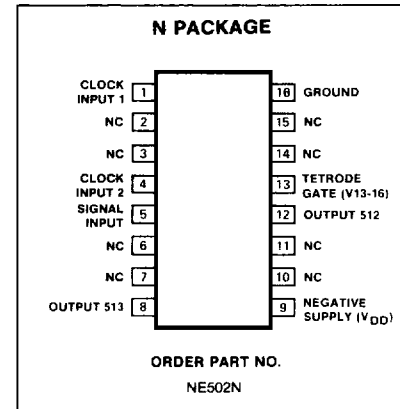
**FEATURES**

- 5 to 500kHz clock frequency
- 512 stages
- Signal delay of 51.2 to .512ms
- Signal frequency to 45kHz

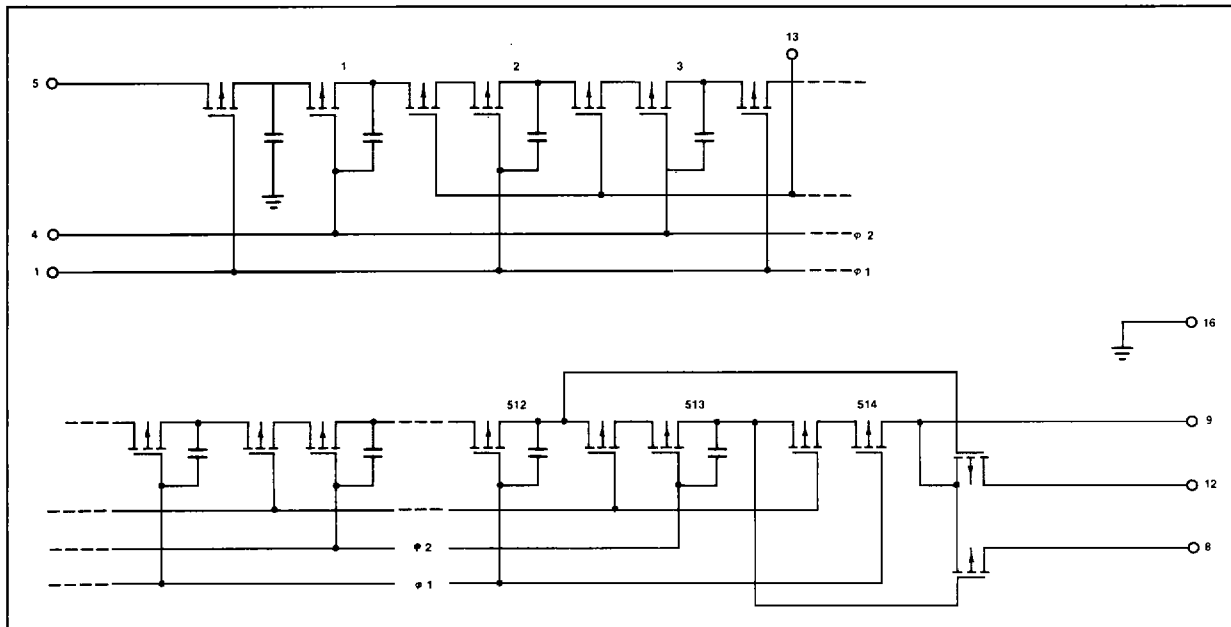
**APPLICATIONS**

- Fixed analog delay
- V<sub>ox</sub> control
- Equalizing speech delay in PA systems
- Vibrato and chorus effects
- Reverberation
- Variable compression/expansion of speech
- Speech scrambling and time scale conversion

**PIN CONFIGURATION**



**EQUIVALENT SCHEMATIC**



**ABSOLUTE MAXIMUM RATINGS**

PARAMETER	RATING	UNIT
V <sub>9-16</sub> Voltages*		
Supply voltage	0 to -20	V
Clock input, data input, output voltage and V <sub>13-16</sub>	0 to -18	V
Current		
I <sub>8,112</sub> Output current	0 to +5	mA
Temperatures		
T <sub>STG</sub> Storage temperature	-40 to +150	°C
T <sub>A</sub> Operating ambient temperature	-20 to +85	°C

\*NOTE

Though MOS integrated circuits incorporate protection against electrostatic discharge, they can nevertheless be damaged by accidental over-voltages. To be totally safe, it is desirable to take handling precautions into account.



**DC ELECTRICAL CHARACTERISTICS**  $T_A = -20^\circ\text{C}$  to  $+55^\circ\text{C}$ ,  $V_{DD} = -15\text{V}$ ,  $V_{\phi 1} = V_{\phi 2} = -15\text{V}$ ,  
 $V_{13-16} = -14\text{V}$ ,  $R_L = 47\text{k}\Omega$  unless otherwise specified.

PARAMETER	TEST CONDITIONS	NE502			UNIT
		Min	Typ	Max	
$V_{DD}$ Supply voltage <sup>1</sup> $I_{DD}$ Supply current		-18	.3	-10	V mA
$V_{\phi 1H}$ , $V_{\phi 2H}$ Clock voltage high $V_{\phi 1L}$ , $V_{\phi 2L}$ Clock voltage low <sup>1</sup>		-1.5 -18	-15	0 -10	V V
$V_{IN}$ Input voltage $R_L$ Load resistance <sup>1</sup>	$V_{OUT} \leq 1\%$ THD	10	2.5 47		Vrms k $\Omega$

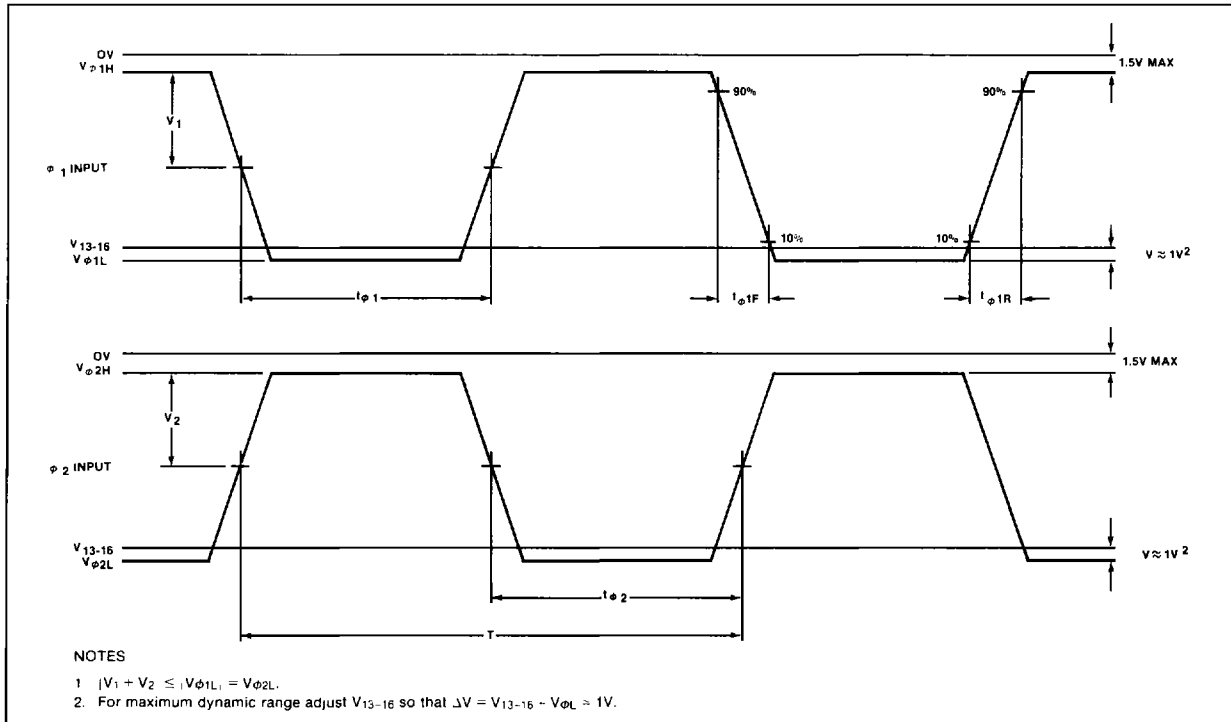
**AC ELECTRICAL CHARACTERISTICS**  $T_A = -20^\circ\text{C}$  to  $+55^\circ\text{C}$ ,  $V_{DD} = -15\text{V}$ ,  $V_{\phi 1} = V_{\phi 2} = -15\text{V}$ ,  
 $V_{13-16} = -14\text{V}$ ,  $R_L = 47\text{k}\Omega$  unless otherwise specified.

PARAMETER	TEST CONDITIONS	NE502			UNIT
		Min	Typ	Max	
$f_{\phi 1}$ , $f_{\phi 2}$ Clock frequency <sup>2</sup>		5		500	kHz
$T_{\phi 1}$ , $T_{\phi 2}$ Clock pulse width <sup>3</sup> $T_{r\phi 1}$ , $T_{r\phi 2}$ Clock rise time <sup>3</sup> $T_{f\phi 1}$ , $T_{f\phi 2}$ Clock fall time <sup>3</sup>			0.05 0.05	.5	T T T
$f_s$ Signal frequency Signal attenuation <sup>1</sup>	$f_{\phi} = 40\text{kHz}$ , $f_s = 1\text{kHz}$	0	4	45 7	kHz dB
Output signal variation Output signal variation	$f_s = 1\text{kHz}$ , $V_s = 1\text{Vrms}$ , $5\text{kHz} \leq f_{\phi} \leq 100\text{kHz}$ $f_s = 1\text{kHz}$ , $V_s = 1\text{Vrms}$ , $100\text{kHz} \leq f_{\phi} \leq 300\text{kHz}$		.5 .5	1 1	dB dB
$\Delta V_{OUT}$ DC voltage shift	$5\text{kHz} \leq f_{\phi} \leq 300\text{kHz}$			.5	V
$V_N$ Noise voltage S/N Signal to noise	$f_{\phi} = 100\text{kHz}$ (weighted by "A" curve)		.25 74		mVrms dB

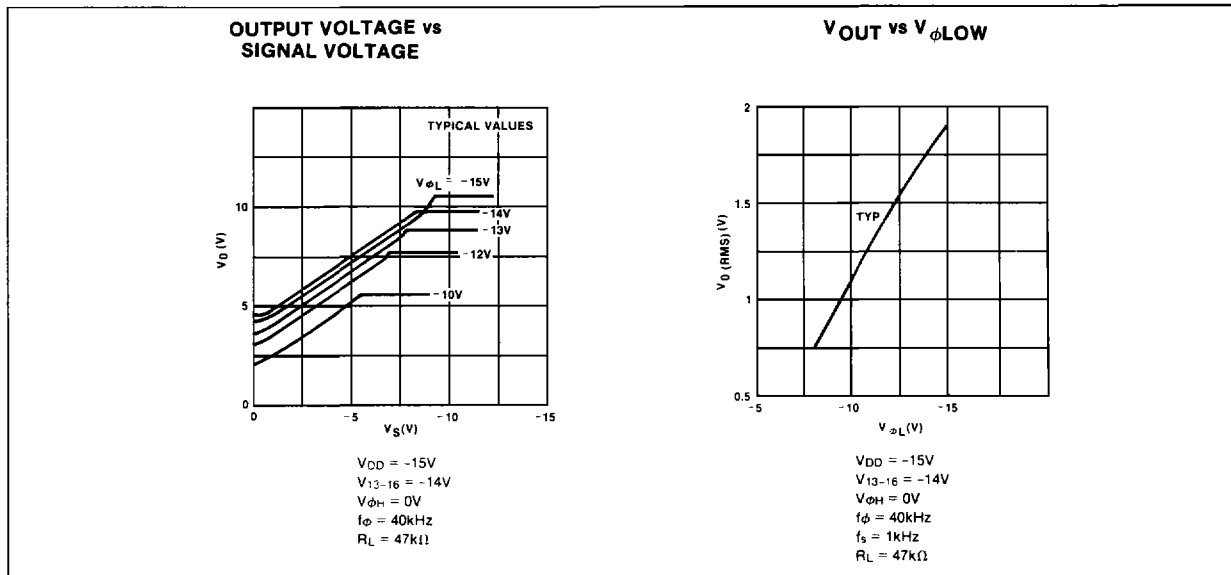
## NOTES

- It is recommended that  $V_{13-16} = V_{\phi 1L} + 1\text{V} = V_{\phi 2L} + 1\text{V}$ ;  $V_{DD}$  more negative than  $V_{\phi L}$ .
- In theory the clock frequency must be higher than twice the highest signal frequency. In practice  $f_s \leq 0.3f_{\phi}$  to  $0.5f_{\phi}$  is recommended, depending on the characteristics of the output filter.
- $T =$  period time  $= 1/f_{\phi}$ . The data on fall and rise times are given to eliminate overlap between the two clock pulses. To be independent of these rise and fall times a clock generator with simple gating can be used. See also pages 5 and 8.

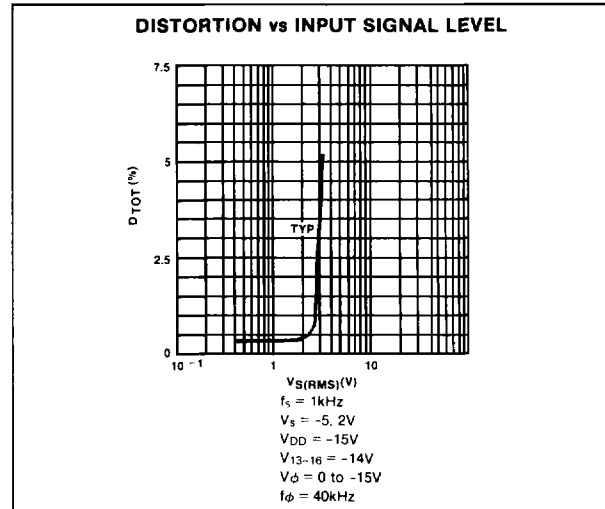
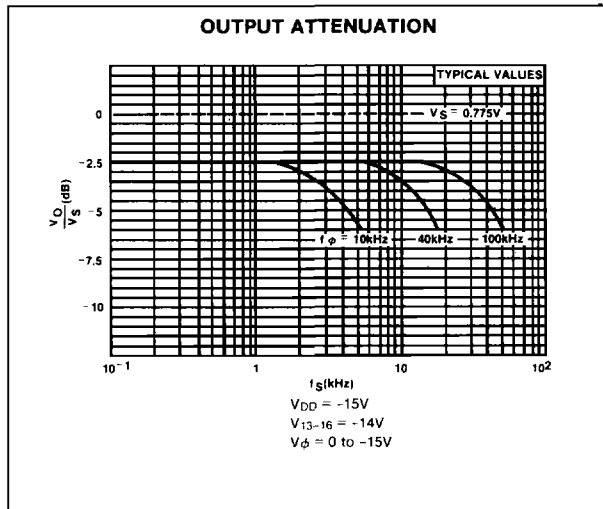
**TIMING DIAGRAM**



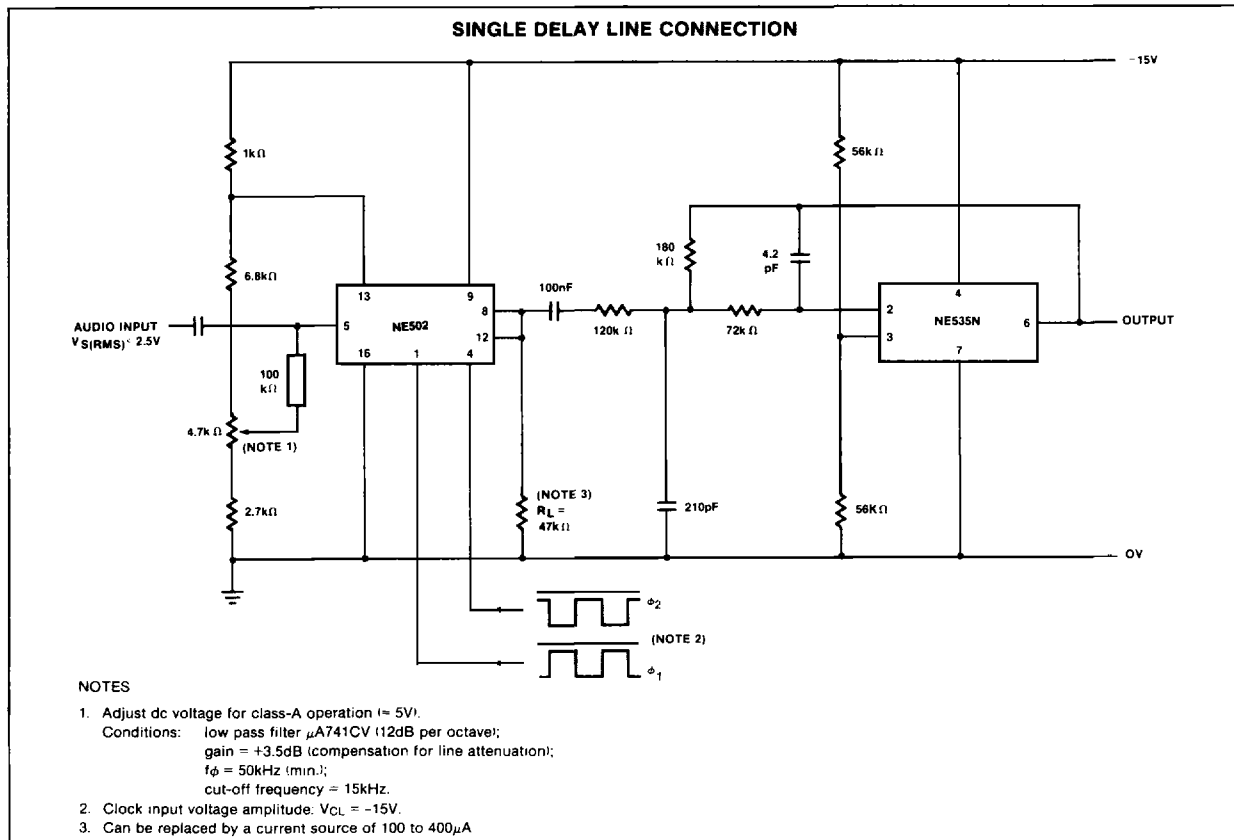
**TYPICAL PERFORMANCE CHARACTERISTICS**



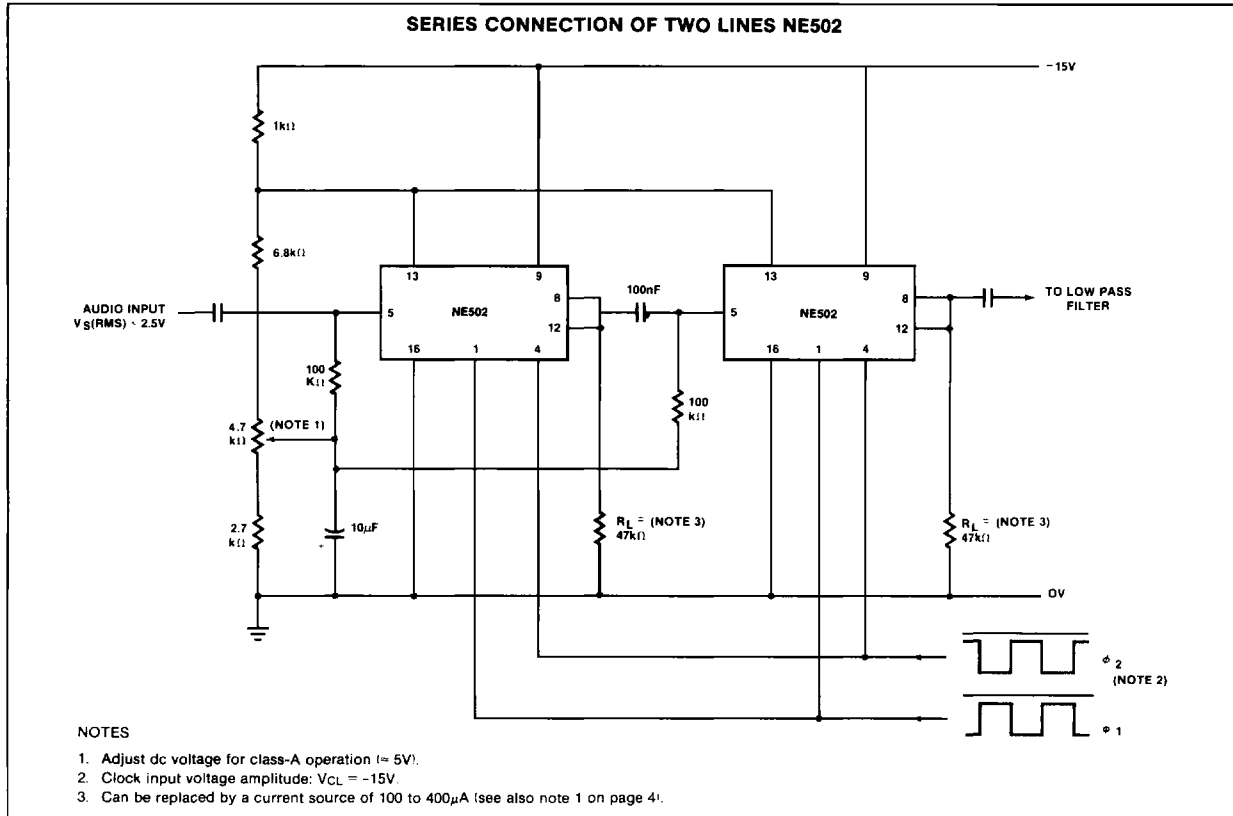
**TYPICAL PERFORMANCE CHARACTERISTICS (Cont'd)**



**TYPICAL APPLICATIONS**



**TYPICAL APPLICATIONS (Cont'd)**



**TYPICAL APPLICATIONS (Cont'd)**

